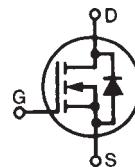
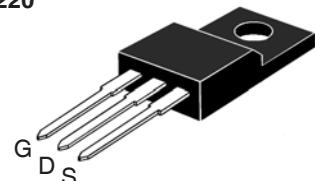


**X-Class HiPERFET
Power MOSFET**
IXFP4N85XM

V_{DSS} = 850V
I_{D25} = 3.5A
R_{DS(on)} ≤ 2.5Ω

(Electrically Isolated Tab)
N-Channel Enhancement Mode

**OVERMOLDED
TO-220**


G = Gate D = Drain
 S = Source

Symbol	Test Conditions	Maximum Ratings	
V _{DSS}	T _J = 25°C to 150°C	850	V
V _{DGR}	T _J = 25°C to 150°C, R _{GS} = 1MΩ	850	V
V _{GSS}	Continuous	±30	V
V _{GSM}	Transient	±40	V
I _{D25}	T _C = 25°C, Limited by T _{JM}	3.5	A
I _{DM}	T _C = 25°C, Pulse Width Limited by T _{JM}	10.0	A
I _A	T _C = 25°C	2	A
E _{AS}	T _C = 25°C	125	mJ
dv/dt	I _S ≤ I _{DM} , V _{DD} ≤ V _{DSS} , T _J ≤ 150°C	50	V/ns
P _D	T _C = 25°C	35	W
T _J		-55 ... +150	°C
T _{JM}		150	°C
T _{stg}		-55 ... +150	°C
T _L	Maximum Lead Temperature for Soldering	300	°C
T _{SOLD}	1.6 mm (0.062in.) from Case for 10s	260	°C
M _d	Mounting Torque	1.13 / 10	Nm/lb.in
Weight		2.5	g

Symbol	Test Conditions (T _J = 25°C, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
BV _{DSS}	V _{GS} = 0V, I _D = 250μA	850		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	3.0		V
I _{GSS}	V _{GS} = ±30V, V _{DS} = 0V			±100 nA
I _{DSS}	V _{DS} = V _{DSS} , V _{GS} = 0V T _J = 125°C			5 μA 500 μA
R _{DS(on)}	V _{GS} = 10V, I _D = 2A, Note 1			2.5 Ω

Features

- International Standard Package
- Plastic Overmolded Tab
- Low R_{DS(ON)} and Q_G
- Avalanche Rated
- Low Package Inductance

Advantages

- High Power Density
- Easy to Mount
- Space Savings

Applications

- Switch-Mode and Resonant-Mode Power Supplies
- DC-DC Converters
- PFC Circuits
- AC and DC Motor Drives
- Robotics and Servo Controls

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max
g_{fs}	$V_{DS} = 10\text{V}$, $I_D = 2\text{A}$, Note 1	1.2	2.0	S
R_{GI}	Gate Input Resistance		3	Ω
C_{iss}	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$	247		pF
C_{oss}		305		pF
C_{rss}		5		pF
Effective Output Capacitance				
$C_{o(er)}$	Energy related } $V_{GS} = 0\text{V}$	27		pF
$C_{o(tr)}$	Time related } $V_{DS} = 0.8 \cdot V_{DSS}$	60		pF
$t_{d(on)}$	$V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 2\text{A}$ $R_G = 30\Omega$ (External)	13		ns
t_r		27		ns
$t_{d(off)}$		28		ns
t_f		20		ns
$Q_{g(on)}$	$V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 2\text{A}$	7.0		nC
Q_{gs}		2.3		nC
Q_{gd}		3.3		nC
R_{thJC}			3.57	$^\circ\text{C}/\text{W}$
R_{thCS}		0.50		$^\circ\text{C}/\text{W}$

Source-Drain Diode

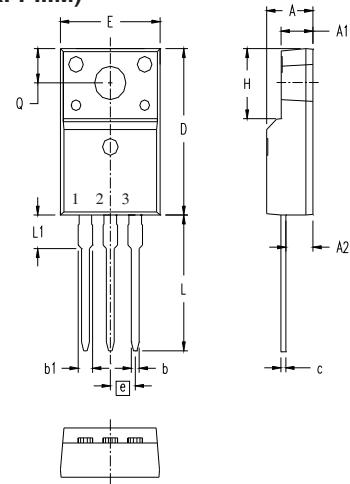
Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max
I_s	$V_{GS} = 0\text{V}$		4	A
I_{SM}	Repetitive, pulse Width Limited by T_{JM}		16	A
V_{SD}	$I_F = I_S$, $V_{GS} = 0\text{V}$, Note 1		1.4	V
t_r	$I_F = 2\text{A}$, $-di/dt = 100\text{A}/\mu\text{s}$ $V_R = 100\text{V}$	170		ns
Q_{RM}		770		nC
I_{RM}		9		A

Note 1. Pulse test, $t \leq 300\mu\text{s}$, duty cycle, $d \leq 2\%$.

ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

OVERMOLDED TO-220 (IXFP...M)



Terminals:
1 - Gate
2 - Drain
3 - Source

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.177	.193	4.50	4.90
A1	.092	.108	2.34	2.74
A2	.101	.117	2.56	2.96
b	.028	.035	0.70	0.90
b1	.050	.058	1.27	1.47
c	.018	.024	0.45	0.60
D	.617	.633	15.67	16.07
E	.392	.408	9.96	10.36
e	.100	BSC	2.54	BSC
H	.255	.271	6.48	6.88
L	.499	.523	12.68	13.28
L1	.119	.135	3.03	3.43
$\emptyset P$.121	.129	3.08	3.28
Q	.126	.134	3.20	3.40

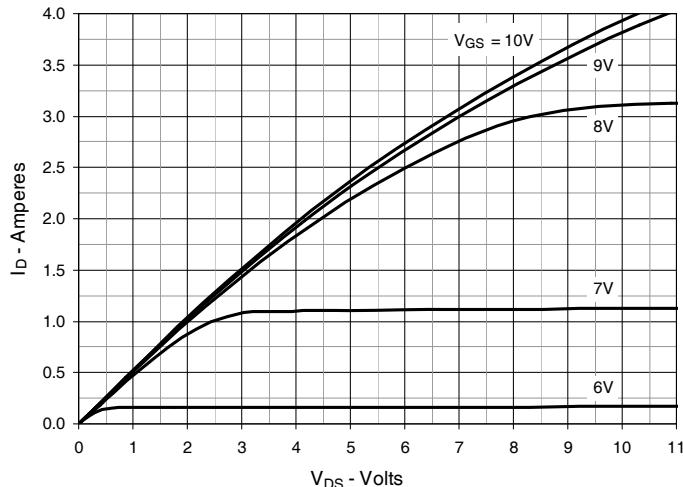
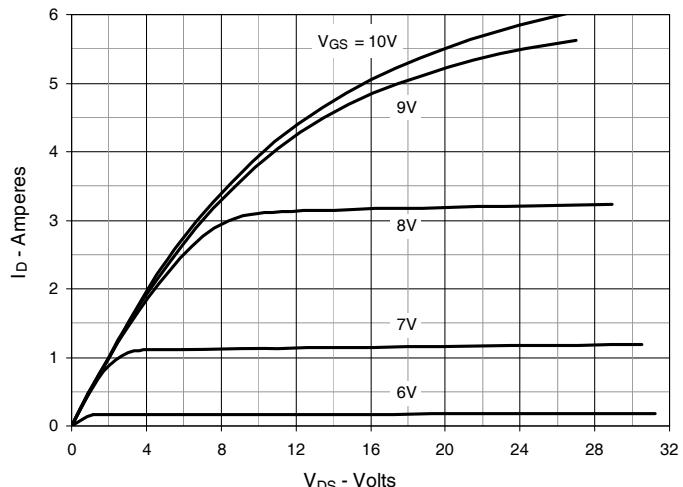
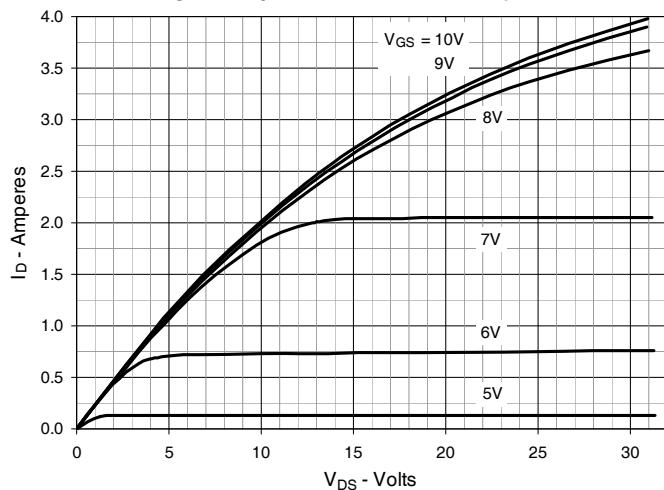
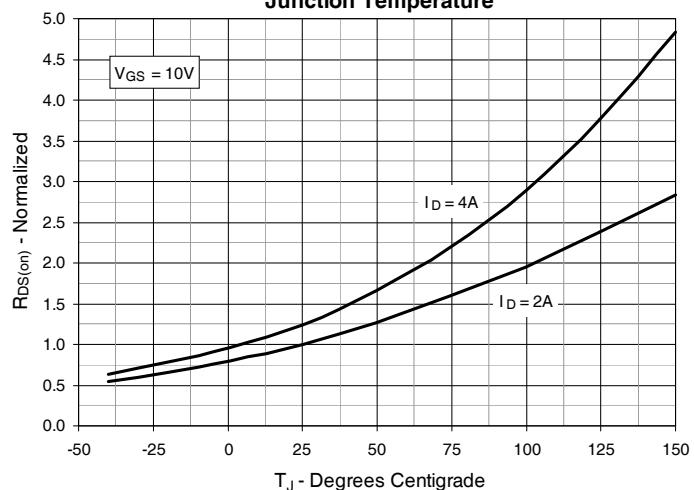
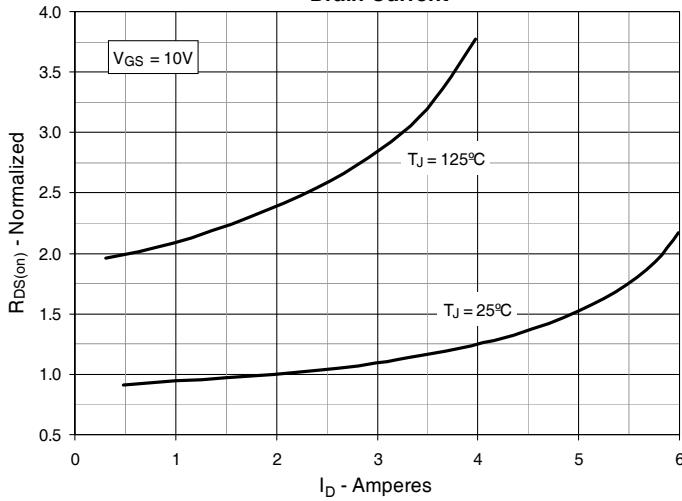
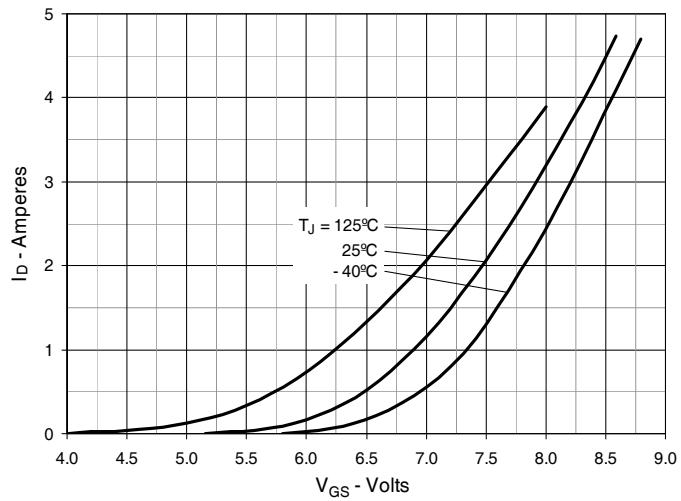
Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$ **Fig. 2. Extended Output Characteristics @ $T_J = 25^\circ\text{C}$** **Fig. 3. Output Characteristics @ $T_J = 125^\circ\text{C}$** **Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 2\text{A}$ Value vs. Junction Temperature****Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 2\text{A}$ Value vs. Drain Current****Fig. 6. Input Admittance**

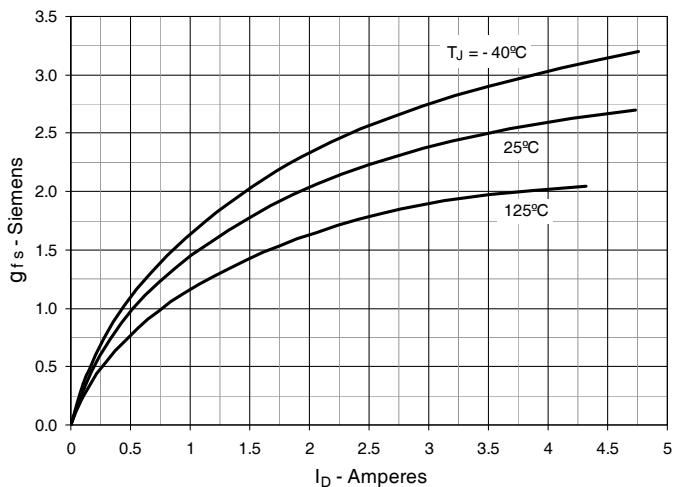
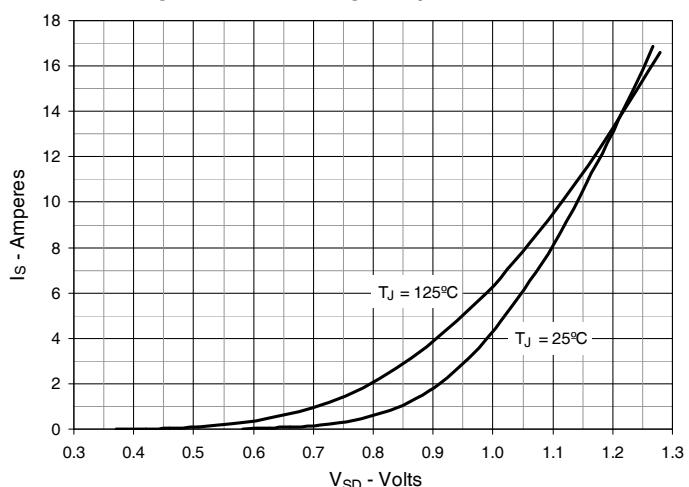
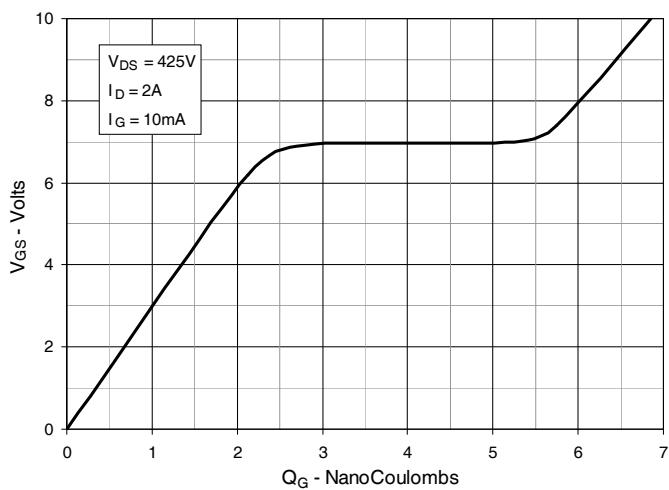
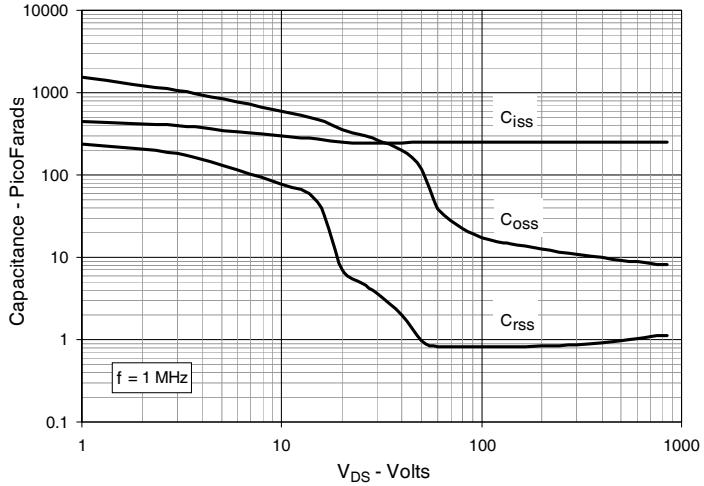
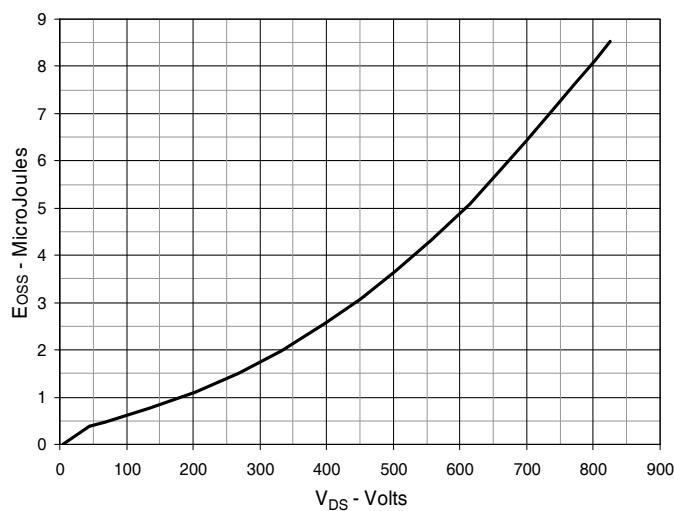
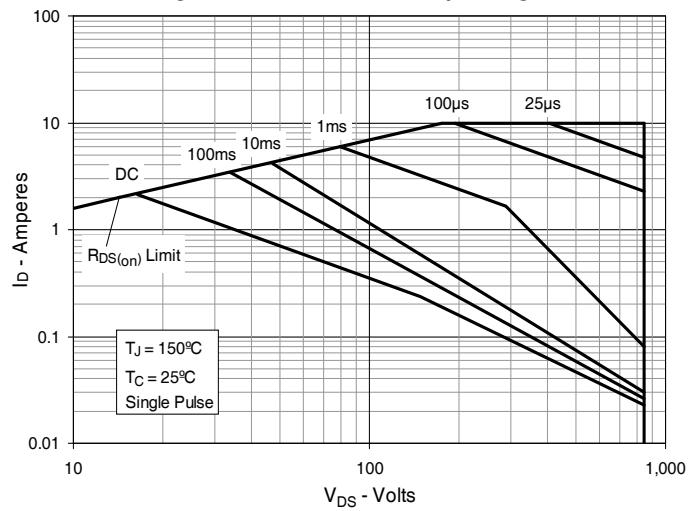
Fig. 7. Transconductance**Fig. 8. Forward Voltage Drop of Intrinsic Diode****Fig. 8. Gate Charge****Fig. 9. Capacitance****Fig. 11. Output Capacitance Stored Energy****Fig. 12. Forward-Bias Safe Operating Area**

Fig. 13. Maximum Transient Thermal Impedance